

# MPS-U05 (SILICON) MPS-U06

## NPN SILICON ANNULAR AMPLIFIER TRANSISTORS

... designed for general-purpose, high-voltage amplifier and driver applications.

- High Collector-Emitter Breakdown Voltage –  
 $V_{CE0} = 60 \text{ Vdc (Min) @ } I_C = 1.0 \text{ mAdc} - \text{MPS-U05}$   
 $80 \text{ Vdc (Min) @ } I_C = 1.0 \text{ mAdc} - \text{MPS-U06}$
- High Power Dissipation –  $P_D = 10 \text{ W @ } T_C = 25^\circ\text{C}$
- Complements to PNP MPS-U55 and MPS-U56

## NPN SILICON AMPLIFIER TRANSISTORS



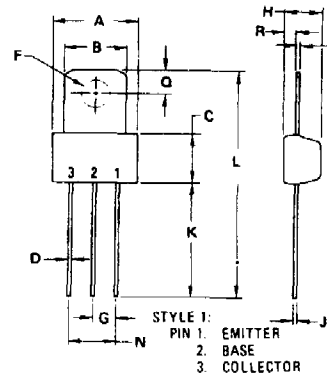
### MAXIMUM RATINGS

| Rating  | Symbol         | MPS-U05     | MPS-U06 | Unit                 |
|---|----------------|-------------|---------|----------------------|
| Collector-Emitter Voltage   | $V_{CE0}$      | 60          | 80      | Vdc                  |
| Collector-Base Voltage  | $V_{CB}$       | 60          | 80      | Vdc                  |
| Emitter-Base Voltage  | $V_{EB}$       |             | 4.0     | Vdc                  |
| Collector Current – Continuous  | $I_C$          |             | 2.0     | Adc                  |
| Total Power Dissipation @ $T_A = 25^\circ\text{C}$<br>Derate above $25^\circ\text{C}$ | $P_D$          |             | 1.0     | Watt                 |
|   |                |             | 8.0     | mW/ $^\circ\text{C}$ |
| Total Power Dissipation @ $T_C = 25^\circ\text{C}$<br>Derate above $25^\circ\text{C}$ | $P_D$          |             | 10      | Watts                |
|   |                |             | 80      | mW/ $^\circ\text{C}$ |
| Operating and Storage Junction<br>Temperature Range                                   | $T_J, T_{stg}$ | -55 to +150 |         | $^\circ\text{C}$     |

### THERMAL CHARACTERISTICS

| Characteristic                          | Symbol                | Max  | Unit               |
|---|-----------------------|------|--------------------|
| Thermal Resistance, Junction to Case    | $R_{\theta JC}$       | 12.5 | $^\circ\text{C/W}$ |
| Thermal Resistance, Junction to Ambient | $R_{\theta JA}^{(1)}$ | 125  | $^\circ\text{C/W}$ |

(1)  $R_{\theta JA}$  is measured with the device soldered into a typical printed circuit board.



| DIM | MILLIMETERS |       | INCHES    |       |
|-----|-------------|-------|-----------|-------|
|     | MIN         | MAX   | MIN       | MAX   |
| A   | 9.14        | 9.53  | 0.360     | 0.375 |
| B   | 6.60        | 7.24  | 0.260     | 0.285 |
| C   | 5.41        | 5.66  | 0.213     | 0.223 |
| D   | 0.38        | 0.53  | 0.015     | 0.021 |
| F   | 3.18        | 3.33  | 0.125     | 0.131 |
| G   | 2.54 BSC    |       | 0.100 BSC |       |
| H   | 3.94        | 4.19  | 0.155     | 0.165 |
| J   | 0.38        | 0.41  | 0.014     | 0.016 |
| K   | 12.07       | 12.70 | 0.475     | 0.500 |
| L   | 25.02       | 25.53 | 0.985     | 1.006 |
| N   | 5.08 BSC    |       | 0.200 BSC |       |
| Q   | 2.39        | 2.69  | 0.094     | 0.106 |
| R   | 1.14        | 1.40  | 0.045     | 0.055 |

CASE 152-02



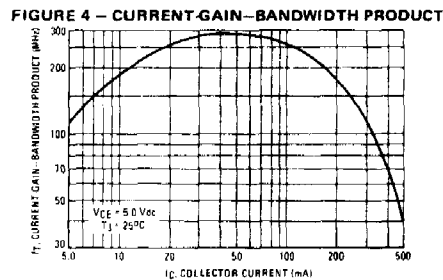
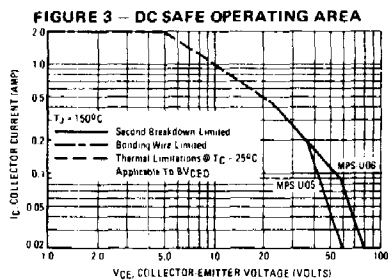
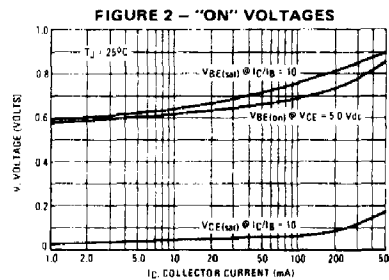
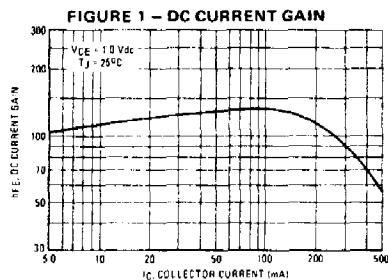
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## MPS-U05, MPS-U06 (continued)

### ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

| Characteristic  | Symbol                           | Min           | Typ              | Max         | Unit |
|---|----------------------------------|---------------|------------------|-------------|------|
| <b>OFF CHARACTERISTICS</b>  |                                  |               |                  |             |      |
| Collector-Emitter Breakdown Voltage<br>( $I_C = 1.0\text{ mAdc}$ , $I_B = 0$ )  | MPS-U05<br>MPS-U06<br>$BV_{CEO}$ | 60<br>80      | —<br>—           | —<br>—      | Vdc  |
| Emitter-Base Breakdown Voltage<br>( $I_E = 100\ \mu\text{Adc}$ , $I_C = 0$ )  | $BV_{EBO}$                       | 4.0           | —                | —           | Vdc  |
| Collector Cutoff Current<br>( $V_{CB} = 40\text{ Vdc}$ , $I_E = 0$ )<br>( $V_{CB} = 60\text{ Vdc}$ , $I_E = 0$ )  | MPS-U05<br>MPS-U06<br>$I_{CBO}$  | —<br>—        | —<br>—           | 100<br>100  | nAdc |
| <b>ON CHARACTERISTICS</b>   |                                  |               |                  |             |      |
| DC Current Gain (1)<br>( $I_C = 50\text{ mAdc}$ , $V_{CE} = 1.0\text{ Vdc}$ )<br>( $I_C = 250\text{ mAdc}$ , $V_{CE} = 1.0\text{ Vdc}$ )<br>( $I_C = 500\text{ mAdc}$ , $V_{CE} = 1.0\text{ Vdc}$ ) | $h_{FE}$                         | 80<br>60<br>— | 125<br>100<br>55 | —<br>—<br>— | —    |
| Collector-Emitter Saturation Voltage (1)<br>( $I_C = 250\text{ mAdc}$ , $I_B = 10\text{ mAdc}$ )<br>( $I_C = 250\text{ mAdc}$ , $I_B = 25\text{ mAdc}$ )  | $V_{CE(sat)}$                    | —<br>—        | 0.18<br>0.1      | 0.4<br>—    | Vdc  |
| Base-Emitter On Voltage (1)<br>( $I_C = 250\text{ mAdc}$ , $V_{CE} = 5.0\text{ Vdc}$ )  | $V_{BE(on)}$                     | —             | 0.74             | 1.2         | Vdc  |
| <b>SMALL-SIGNAL CHARACTERISTICS</b>   |                                  |               |                  |             |      |
| Current-Gain-Bandwidth Product (1)<br>( $I_C = 200\text{ mAdc}$ , $V_{CE} = 5.0\text{ Vdc}$ , $f = 100\text{ MHz}$ )  | $f_T$                            | 50            | 170              | —           | MHz  |
| Output Capacitance<br>( $V_{CB} = 10\text{ Vdc}$ , $I_C = 0$ , $f = 100\text{ kHz}$ )   | $C_{ob}$                         | —             | 6.0              | 12          | pF   |

(1) Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .



There are two limitations on the power handling ability of a transistor: junction temperature and second breakdown. Safe operating area curves indicate  $I_C - V_{CE}$  limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 3 is based on  $T_J(\text{pk}) = 150^\circ\text{C}$ ;  $T_C$  is variable depending on conditions. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.